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# STD22NM20N

## N-CHANNEL 200V - 0.088Ω - 22A DPAK ULTRA LOW GATE CHARGE MDmesh™ II MOSFET

**Table 1: General Features**

| TYPE       | V <sub>DSS</sub> | R <sub>DS(on)</sub> | I <sub>D</sub> |
|------------|------------------|---------------------|----------------|
| STD22NM20N | 200 V            | < 0.105 Ω           | 22 A           |

- WORLDWIDE LOWEST GATE CHARGE
- TYPICAL R<sub>DS(on)</sub> = 0.088 Ω
- HIGH dv/dt and AVALANCHE CAPABILITIES
- LOW INPUT CAPACITANCE
- LOW GATE RESISTANCE

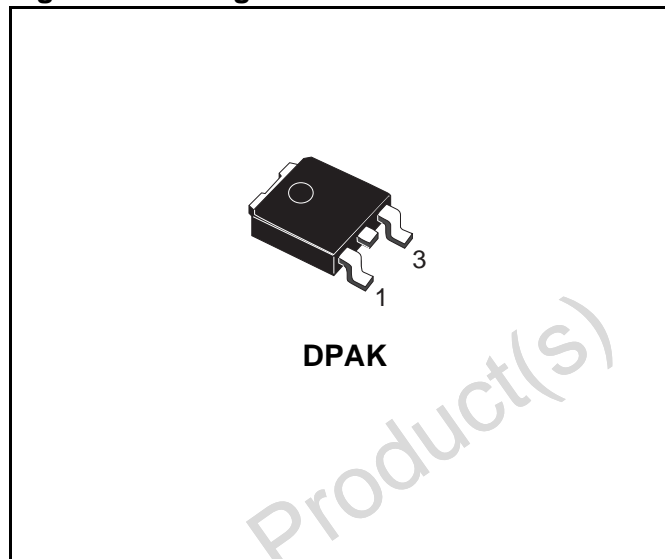
### DESCRIPTION

This 200V MOSFET with a new advanced layout brings all unique advantages of MDmesh technology to lower voltages. The device exhibits worldwide lowest gate charge for any given on-resistance. Its use is therefore ideal as primary switch in isolated DC-DC converters for Telecom and Computer applications. Used in combination with secondary-side low-voltage STripFET™ products, it contributes to reducing losses and boosting efficiency.

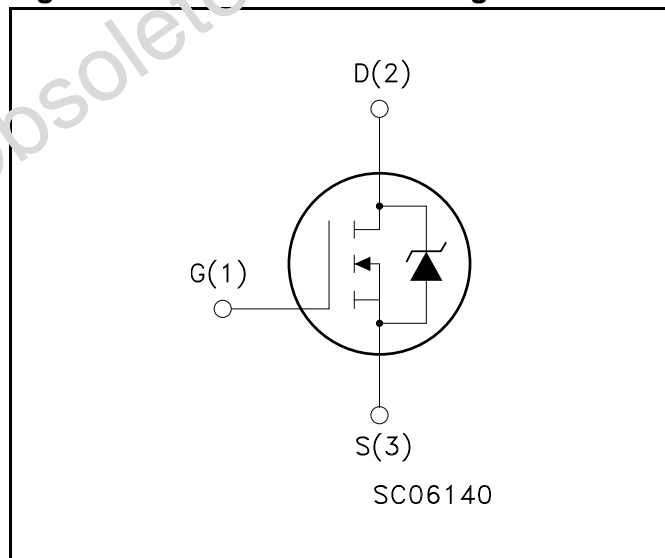
### APPLICATIONS

The MDmesh™ family is very suitable for increasing power density allowing system miniaturization and higher efficiencies

**Figure 1: Package**



**Figure 2: Internal Schematic Diagram**



**Table 2: Order Codes**

| SALES TYPE   | MARKING  | PACKAGE | PACKAGING   |
|--------------|----------|---------|-------------|
| STD22NM20NT4 | D22NM20N | DPAK    | TAPE & REEL |

**STD22NM20N**
**Table 3: Absolute Maximum ratings**

| Symbol             | Parameter   | Value      | Unit                |
|--------------------|---|------------|---------------------|
| $V_{DS}$           | Drain-source Voltage ( $V_{GS} = 0$ )               | 200        | V                   |
| $V_{DGR}$          | Drain-gate Voltage ( $R_{GS} = 20\text{ k}\Omega$ ) | 200        | V                   |
| $V_{GS}$           | Gate- source Voltage                                | $\pm 20$   | V                   |
| $I_D$              | Drain Current (continuous) at $T_C = 25^\circ$      | 22         | A                   |
|                    | Drain Current (continuous) at $T_C = 100^\circ$     | 13.7       | A                   |
| $I_{DM} (*)$       | Drain Current (pulsed)                              | 88         | A                   |
| $P_{TOT}$          | Total Dissipation at $T_C = 25^\circ\text{C}$       | 100        | W                   |
|                    | Derating Factor                                     | 0.8        | W/ $^\circ\text{C}$ |
| $dv/dt (2)$        | Peak Diode Recovery voltage slope                   | 14         | V/ns                |
| $T_j$<br>$T_{stg}$ | Storage Temperature                                 | 150        | $^\circ\text{C}$    |
|                    | Max Operating Junction Temperature                  | -65 to 150 | $^\circ\text{C}$    |

 (\*)  $I_{SD} \leq 22\text{A}$ ,  $di/dt \leq 400\text{A}/\mu\text{s}$ ,  $V_{DD} = 80\% V_{(BR)DSS}$ 
**Table 4: Thermal Data**

|                        |  |      |                           |
|------------------------|--|------|---------------------------|
| Rthj-case              | Thermal Resistance Junction-case Max           | 1.25 | $^\circ\text{C}/\text{W}$ |
| Rthj-amb               | Thermal Resistance Junction-ambient Max        | 100  | $^\circ\text{C}/\text{W}$ |
| Rthj-ambT <sub>l</sub> | Thermal Resistance Junction-pcb (*)            | 43   | $^\circ\text{C}/\text{W}$ |
|                        | Maximum Lead Temperature For Soldering Purpose | 275  | $^\circ\text{C}$          |

 (\*) When mounted on 1 inch<sup>2</sup> FR-4 board, 2 oz Cu,  $t \leq 10\text{ sec}$ 
**Table 5: Avalanche Characteristics**

| Symbol   | Parameter   | Max Value | Unit |
|----------|---|-----------|------|
| $I_{AS}$ | Avalanche Current, Repetitive or Not-Repetitive (pulse width limited by $T_j$ max)                                | 22        | A    |
| $E_{AS}$ | Single Pulse Avalanche Energy (starting $T_j = 25^\circ\text{C}$ , $I_D = 22\text{ A}$ , $V_{DD} = 50\text{ V}$ ) | 380       | mJ   |

**ELECTRICAL CHARACTERISTICS** ( $T_{CASE} = 25^{\circ}C$  UNLESS OTHERWISE SPECIFIED)

**Table 6: On/Off**

| Symbol        | Parameter  | Test Conditions  | Min. | Typ.  | Max.    | Unit               |
|---------------|--|--|------|-------|---------|--------------------|
| $V_{(BR)DSS}$ | Drain-source Breakdown Voltage                   | $I_D = 1mA, V_{GS} = 0$  | 200  |       |         | V                  |
| $I_{DSS}$     | Zero Gate Voltage Drain Current ( $V_{GS} = 0$ ) | $V_{DS} = \text{Max Rating}$<br>$V_{DS} = \text{Max Rating}, T_C = 125^{\circ}C$ |      |       | 1<br>10 | $\mu A$<br>$\mu A$ |
| $I_{GSS}$     | Gate-body Leakage Current ( $V_{DS} = 0$ )       | $V_{GS} = \pm 20V$   |      |       | 100     | nA                 |
| $V_{GS(th)}$  | Gate Threshold Voltage                           | $V_{DS} = V_{GS}, I_D = 250 \mu A$   | 3.5  | 4.2   | 5       | V                  |
| $R_{DS(on)}$  | Static Drain-source On Resistance                | $V_{GS} = 10V, I_D = 11 A$   |      | 0.088 | 0.105   | $\Omega$           |

**Table 7: Dynamic**

| Symbol   | Parameter   | Test Conditions   | Min. | Typ.                 | Max. | Unit                 |
|--|---|---|------|----------------------|------|----------------------|
| $g_{fs} (2)$                                   | Forward Transconductance  | $V_{DS} = 15 V, I_D = 11 A$   |      | 8                    |      | S                    |
| $C_{iss}$<br>$C_{oss}$<br>$C_{rss}$            | Input Capacitance<br>Output Capacitance<br>Reverse Transfer Capacitance | $V_{DS} = 25V, f = 1 \text{ MHz}, V_{GS} = 0$                                       |      | 800<br>330<br>130    |      | pF<br>pF<br>pF       |
| $C_{oss \text{ eq.}} (**)$                     | Equivalent Output Capacitance   | $V_{GS} = 0 V, V_{DS} = 0 V \text{ to } 400 V$                                      |      | 225                  |      | pF                   |
| $R_G$  | Gate Input Resistance   | $f = 1\text{MHz}$ Gate DC Bias = 0<br>Test Signal Level = 20 mV<br>Open Drain       |      | 5                    |      | $\Omega$             |
| $t_{d(on)}$<br>$t_r$<br>$t_{r(Voff)}$<br>$t_f$ | Turn-on Delay Time<br>Rise Time<br>Turn-off Delay Time<br>Fall Time     | $V_{DD} = 100 V, I_D = 11 A$<br>$R_G = 4.7\Omega, V_{GS} = 10 V$<br>(see Figure 15) |      | 40<br>15<br>40<br>11 |      | ns<br>ns<br>ns<br>ns |
| $Q_g$<br>$Q_{gs}$<br>$Q_{gd}$                  | Total Gate Charge<br>Gate-Source Charge<br>Gate-Drain Charge            | $V_{DD} = 100 V, I_D = 20 A,$<br>$V_{GS} = 10 V$<br>(see Figure 19)                 |      | 32<br>6<br>25        | 50   | nC<br>nC<br>nC       |

(\*\*)  $C_{oss \text{ eq.}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$

**Table 8: Source Drain Diode**

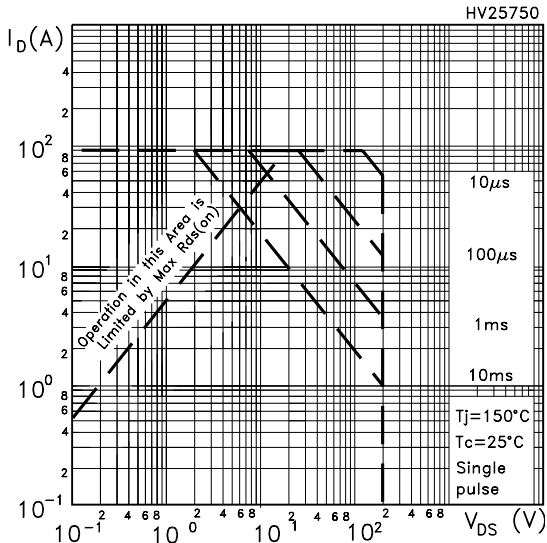
| Symbol                            | Parameter  | Test Conditions  | Min. | Typ.               | Max.     | Unit               |
|-----------------------------------|--|--|------|--------------------|----------|--------------------|
| $I_{SD}$<br>$I_{SDM} (1)$         | Source-drain Current<br>Source-drain Current (pulsed)                        |  |      |                    | 22<br>88 | A<br>A             |
| $V_{SD} (2)$                      | Forward On Voltage   | $I_{SD} = 20 A, V_{GS} = 0$  |      |                    | 1.3      | V                  |
| $t_{rr}$<br>$Q_{rr}$<br>$I_{RRM}$ | Reverse Recovery Time<br>Reverse Recovery Charge<br>Reverse Recovery Current | $I_{SD} = 20 A, di/dt = 100 A/\mu s$<br>$V_{DD} = 100V, T_j = 25^{\circ}C$<br>(see test circuit, Figure 17)  |      | 160<br>960<br>12.8 |          | ns<br>$\mu C$<br>A |
| $t_{rr}$<br>$Q_{rr}$<br>$I_{RRM}$ | Reverse Recovery Time<br>Reverse Recovery Charge<br>Reverse Recovery Current | $I_{SD} = 20 A, di/dt = 100 A/\mu s$<br>$V_{DD} = 100V, T_j = 150^{\circ}C$<br>(see test circuit, Figure 17) |      | 225<br>1642<br>15  |          | ns<br>$\mu C$<br>A |

(1) Pulse width limited by safe operating area.

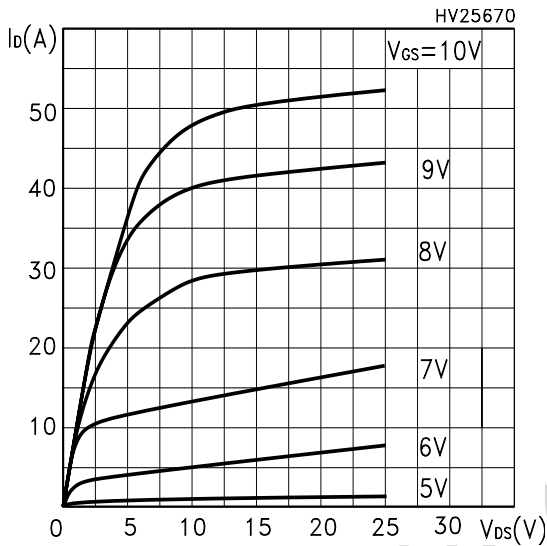
(2) Pulsed: Pulse duration = 300  $\mu s$ , duty cycle 1.5 %

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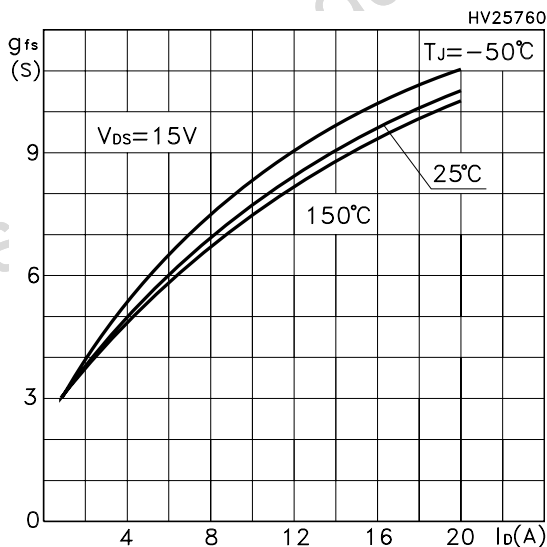
**Figure 3: Safe Operating Area**



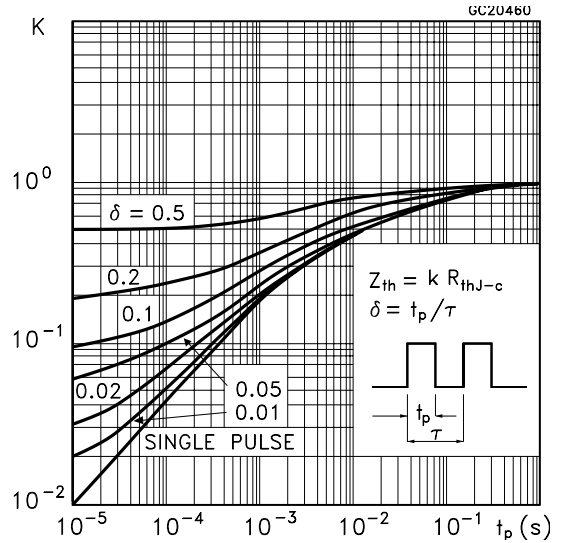
**Figure 4: Output Characteristics**



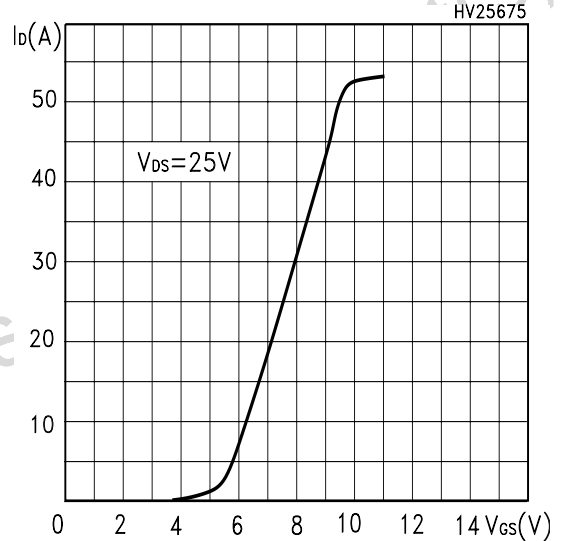
**Figure 5: Transconductance**



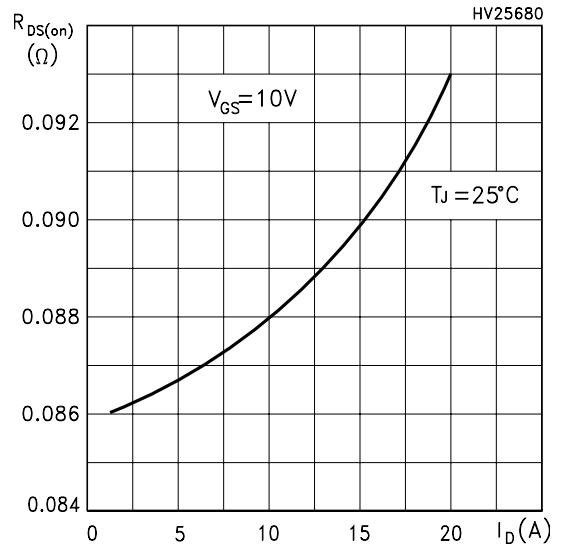
**Figure 6: Thermal Impedance**



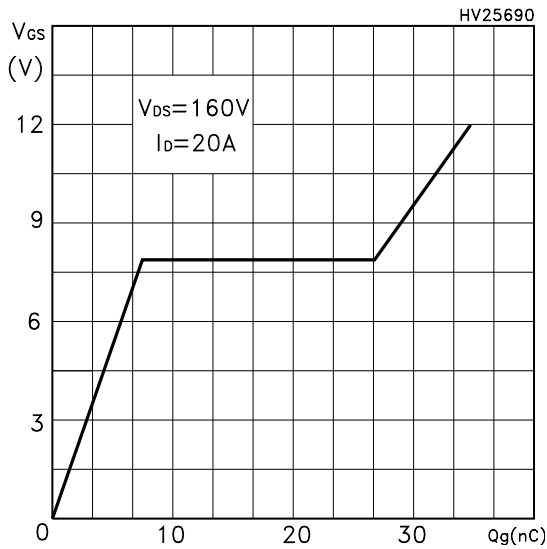
**Figure 7: Transfer Characteristics**



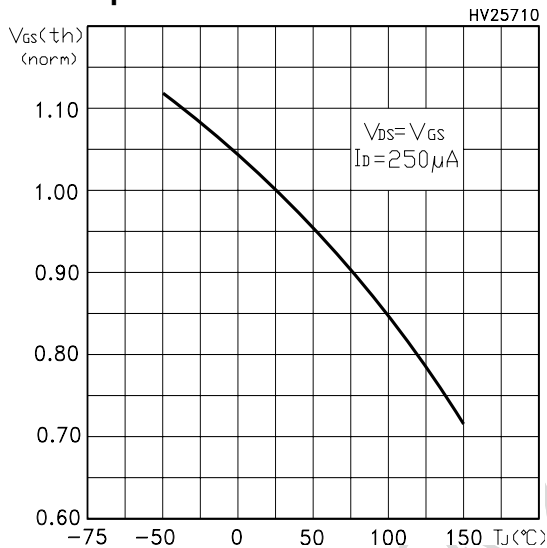
**Figure 8: Static Drain-source On Resistance**



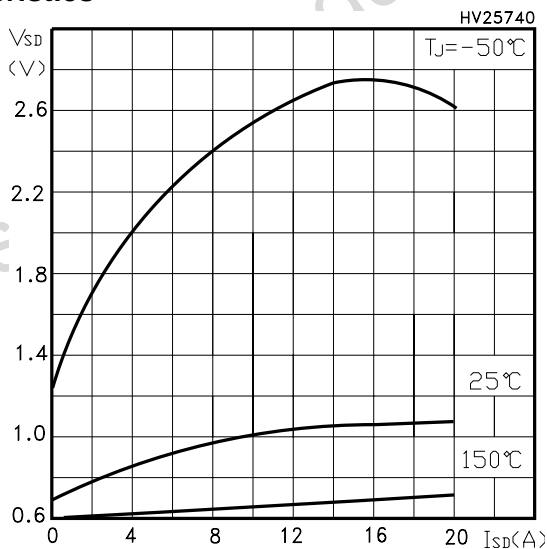
**Figure 9: Gate Charge vs Gate-source Voltage**



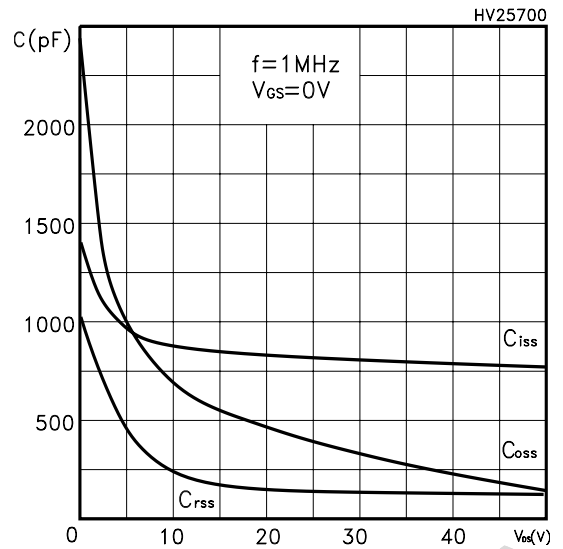
**Figure 10: Normalized Gate Threshold Voltage vs Temperature**



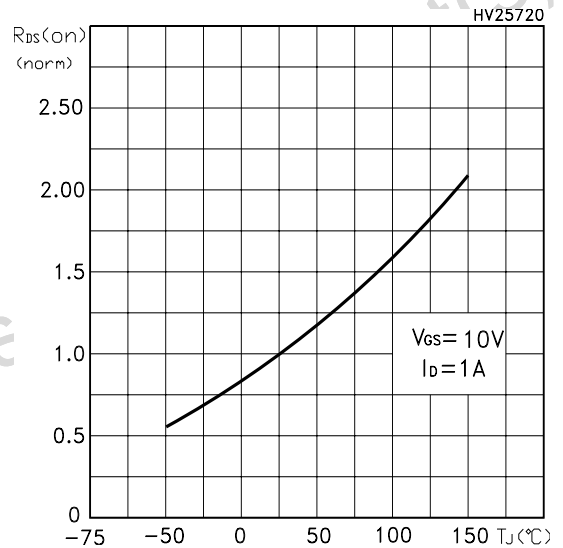
**Figure 11: Source-Drain Diode Forward Characteristics**



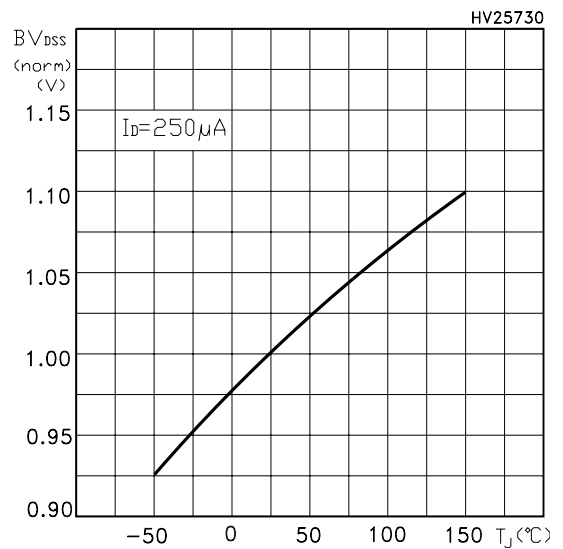
**Figure 12: Capacitance Variations**



**Figure 13: Normalized On Resistance vs Temperature**

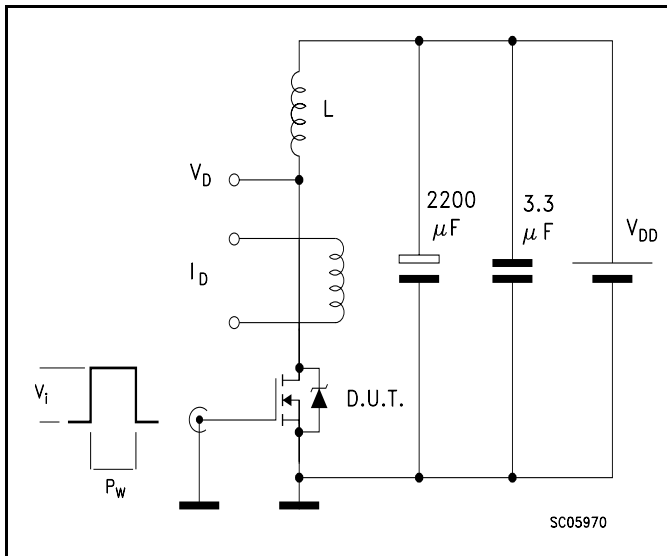


**Figure 14: Normalized BVdss vs Temperature**

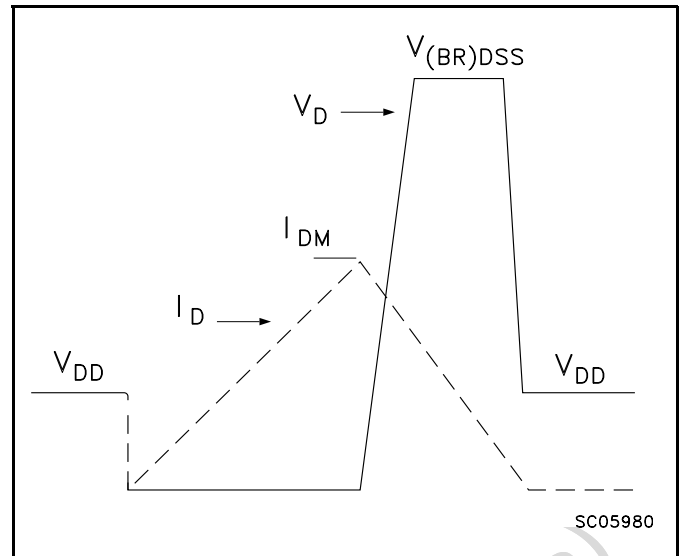


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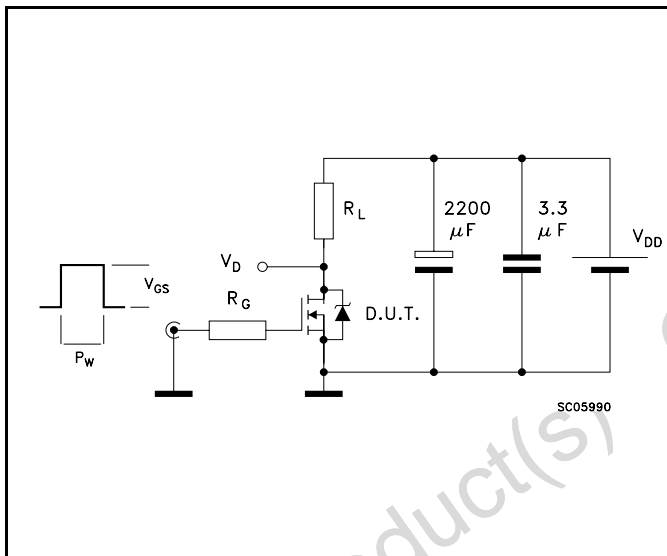
**Figure 15: Unclamped Inductive Load Test Circuit**



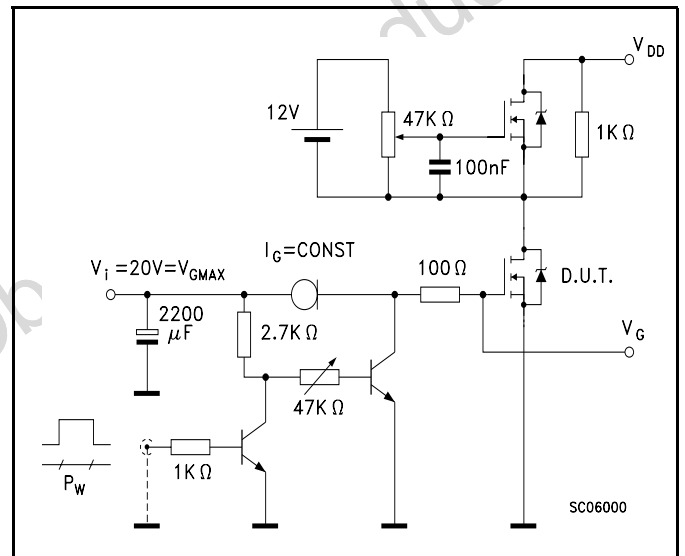
**Figure 18: Unclamped Inductive Wafeform**



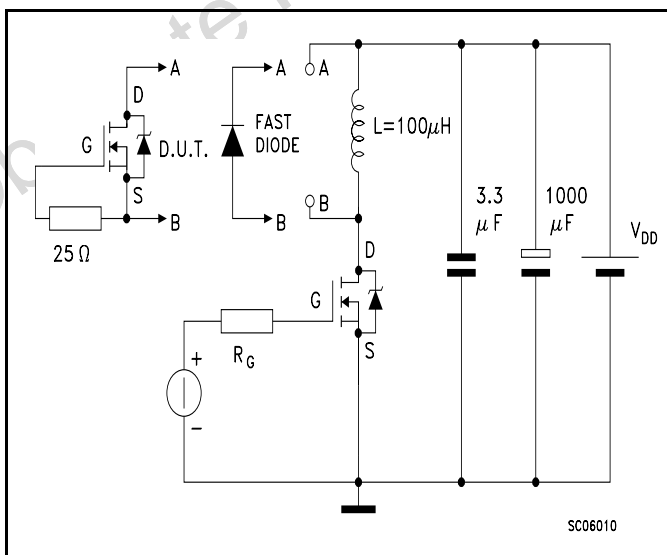
**Figure 16: Switching Times Test Circuit For Resistive Load**



**Figure 19: Gate Charge Test Circuit**

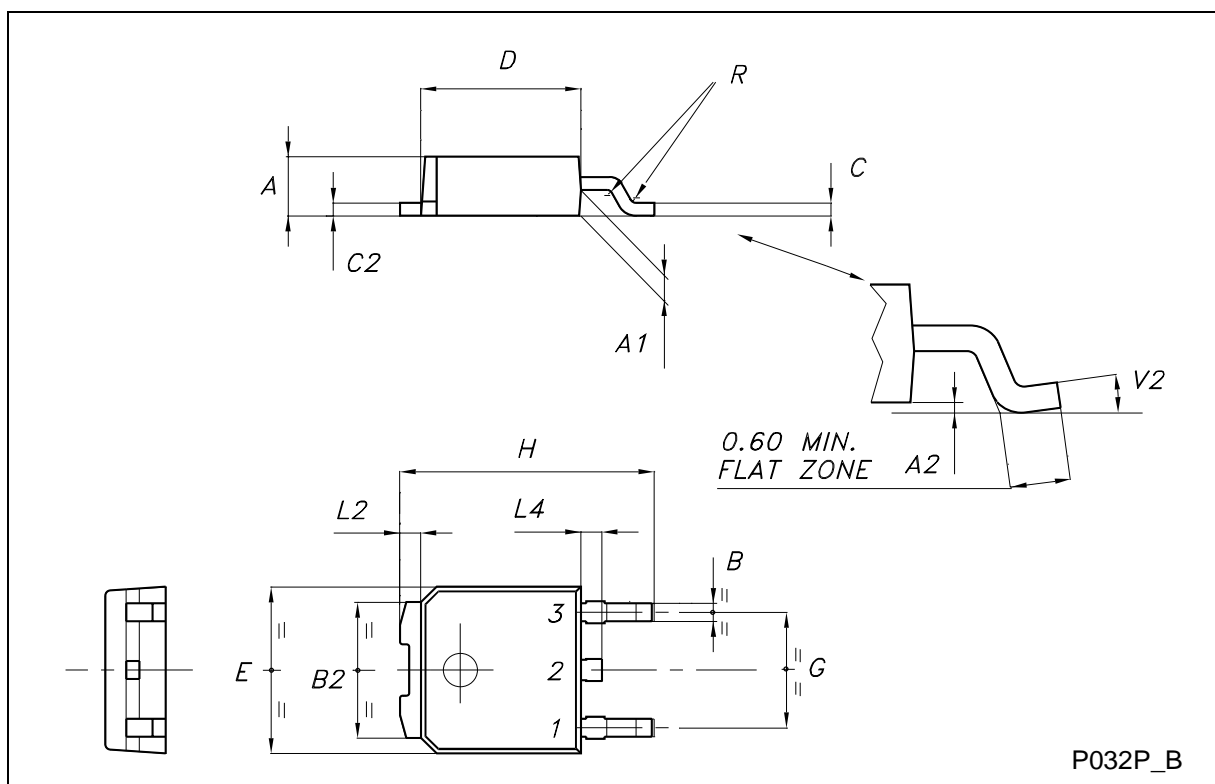


**Figure 17: Test Circuit For Inductive Load Switching and Diode Recovery Times**



**TO-252 (DPAK) MECHANICAL DATA**

| DIM. | mm   |      |       | inch  |       |       |
|------|------|------|-------|-------|-------|-------|
|      | MIN. | TYP. | MAX.  | MIN.  | TYP.  | MAX.  |
| A    | 2.20 |      | 2.40  | 0.087 |       | 0.094 |
| A1   | 0.90 |      | 1.10  | 0.035 |       | 0.043 |
| A2   | 0.03 |      | 0.23  | 0.001 |       | 0.009 |
| B    | 0.64 |      | 0.90  | 0.025 |       | 0.035 |
| B2   | 5.20 |      | 5.40  | 0.204 |       | 0.213 |
| C    | 0.45 |      | 0.60  | 0.018 |       | 0.024 |
| C2   | 0.48 |      | 0.60  | 0.019 |       | 0.024 |
| D    | 6.00 |      | 6.20  | 0.236 |       | 0.244 |
| E    | 6.40 |      | 6.60  | 0.252 |       | 0.260 |
| G    | 4.40 |      | 4.60  | 0.173 |       | 0.181 |
| H    | 9.35 |      | 10.10 | 0.368 |       | 0.398 |
| L2   |      | 0.8  |       |       | 0.031 |       |
| L4   | 0.60 |      | 1.00  | 0.024 |       | 0.039 |
| V2   | 0°   |      | 8°    | 0°    |       | 0°    |







**Table 9: Revision History**

| <b>Date</b> | <b>Revision</b> | <b>Description of Changes</b> |
|-------------|-----------------|-------------------------------|
| 31-May-2004 | 1               | First Release.                |
| 15-Mar-2005 | 2               | Update version.               |
| 09-May-2005 | 3               | Complete version.             |
| 09-Jun-2005 | 4               | New update                    |
| 04-Nov-2005 | 5               | Corrected value on Table 8    |

Obsolete Product(s) - Obsolete Product(s)

## STD22NM20N

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